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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/722,400	11/27/2000	Tianhong Zhang	MIC-58DV2	5784	
7:	590 03/11/2004		EXAM	INER	
Rajesh Vallabh, Esq.			MOHAMEDULLA, SALEHA R		
Hale and Dorr I 60 State Street	LLP		ART UNIT	PAPER NUMBER	
Boston, MA 02109			1756		
			DATE MAILED: 03/11/200	DATE MAILED: 03/11/2004	

Please find below and/or attached an Office communication concerning this application or proceeding.

The same of the sa	Application No.	Applicant(s)				
Advisory Action	09/722,400	ZHANG ET AL.				
Advisory Action	Examiner	Art Unit				
·	Saleha R. Mohamedulla	1756				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address						
THE REPLY FILED 13 February 2004 FAILS TO PLACE THIS APPLICATION IN CONDITION FOR ALLOWANCE. Therefore, further action by the applicant is required to avoid abandonment of this application. A proper reply to a final rejection under 37 CFR 1.113 may only be either: (1) a timely filed amendment which places the application in condition for allowance; (2) a timely filed Notice of Appeal (with appeal fee); or (3) a timely filed Request for Continued Examination (RCE) in compliance with 37 CFR 1.114.						
PERIOD FOR REPLY [check either a) or b)]						
a) The period for reply expires <u>5</u> months from the mailing date of the final rejection.						
b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire I ONLY CHECK THIS BOX WHEN THE FIRST REPLY WAS 706.07(f).  Extensions of time may be obtained under 37 CFR 1.136(a). The fee have been filed is the date for purposes of determining the period of the under 37 CFR 1.17(a) is calculated from: (1) the expiration date of (2) as set forth in (b) above, if checked. Any reply received by the Official filed, may reduce any earned patent term adjustment. See 37 CFR 1.17(a) is calculated from: (1) the expiration date of (2) as set forth in (b) above, if checked. Any reply received by the Official filed, may reduce any earned patent term adjustment.	ater than SIX MONTHS from the mailing FILED WITHIN TWO MONTHS OF THe date on which the petition under 37 CF of extension and the corresponding amo the shortened statutory period for reply the later than three months after the mail	g date of the final rejection. HE FINAL REJECTION. See MPEP  R 1.136(a) and the appropriate extension unt of the fee. The appropriate extension originally set in the final Office action; or				
1. A Notice of Appeal was filed on <u>13 February 2004</u> . Appellant's Brief must be filed within the period set forth in 37 CFR 1.192(a), or any extension thereof (37 CFR 1.191(d)), to avoid dismissal of the appeal.						
2. The proposed amendment(s) will not be entered be	ecause:					
(a) they raise new issues that would require further consideration and/or search (see NOTE below);						
(b) they raise the issue of new matter (see Note below);						
(c) they are not deemed to place the application in better form for appeal by materially reducing or simplifying the issues for appeal; and/or						
(d)  they present additional claims without canceli NOTE:	ng a corresponding number of fi	nally rejected claims.				
3. Applicant's reply has overcome the following reject	ion(s): <u>NONE</u> .					
4. Newly proposed or amended claim(s) would canceling the non-allowable claim(s).	be allowable if submitted in a se	eparate, timely filed amendment				
5.⊠ The a) affidavit, b) exhibit, or c) request for reconsideration has been considered but does NOT place the application in condition for allowance because: See Continuation Sheet.						
6. The affidavit or exhibit will NOT be considered becaraised by the Examiner in the final rejection.	ause it is not directed SOLELY t	o issues which were newly				
7. For purposes of Appeal, the proposed amendment explanation of how the new or amended claims we						
The status of the claim(s) is (or will be) as follows:						
Claim(s) allowed: NONE.		•				
Claim(s) objected to: NONE.						
Claim(s) rejected: <u>9-12,27,29-40 and 42-50</u> .		·				
Claim(s) withdrawn from consideration: NONE.						
8.☐ The drawing correction filed on is a)☐ appr	roved or b) disapproved by t	he Examiner.				
9. Note the attached Information Disclosure Statemer	nt(s)( PTO-1449) Paper No(s)					
10.						
	·					
		,				

Continuation of 5. does NOT place the application in condition for allowance because:

Applicant argues that the openings in Tsutsui are not openings therethrough because the openings do not extend through a layer of material resistant to the claimed etchant. However, the openings in Tsutsui extend through the layer resistant to the etchant. On either side of the Au-WSi layer, there are complete openings, that is, openings that extend all the way through the openings, as the Au-WSi layer

does not exist in these openings.

Applicant argues that the layer is not a masking layer, however, the layer is a mask as the layer is not etched while underlying layers are etched and because they cover or mask underlying layers. Applicant attempts to define the term "mask" in arguments, however, this definition is not supported by the original disclosure. Applicant states that it is well known that masks permit selective removal of material underneath the structure, but provides no support for such an exclusive limited definition. Within the semiconductor processing art, the the term "mask" is not solely limited to the use and definition offered by Applicant. As already stated, the Tsutsui structure is a mask because the layer is not etched while underlying layers are etched and because they cover or mask underlying layers. In addition, the layer is used in the deposition of layer 10 and is therefore a mask in this respect as well. In addition, Figure 5 shows the WSi layer, a layer made of material resistant to the claimed etchant, used as a structure that permits selective removal of material underneath the structure (Applicant's definition of mask).

Applicant argues that no use of hydrogen fluoride etchant is disclosed when discussing the etching. However, the invention of Tsutsui is specifically directed to hydrogen fluoride etching. The title of the Tsutsui invention is "Hydrogen Fluoride Vapor Phase Selective Etching Method for Fabricating Semiconductor Devices."

Applicant argues that there is no motivation to combineTsutsui and Farnworth. However, Farnworth teaches that the specific material of a polyimide is commonly known in the art for the application of Tsutsui. The references are analogous art as they are both drawn to patterning semiconductior layers using photosensitive and etching processes. Applicant argues that there is no motivation to combine Tsutsui and Cloud. However, the references are analogous art as they are drawn to forming gate structures for semiconductor devices and Cloud teaches the desireability of using the claimed polyimide.

Therefore, Applicant's arguments are not persuasive.

MÖHAMEDULLA, SALEHATA PATENT EXAMINER

3/5764

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